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Drawing
3/26/03
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UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : **Confirmation No. 6344**
Yoshio YANASE et al. : **Docket No. 2001-0615A**
Serial No. 09/856,982 : **[Group Art Unit 2877]**
Filed May 30, 2001 : **Examiner Sang H. Nguyen]**

METHOD FOR INSPECTING SEMICONDUCTOR WAFER SURFACE

*Approved by examiner (05/15/03)
SN*

SUBMISSION OF FORMAL DRAWINGS

Assistant Commissioner for Patents,
Washington, DC 20231

THE COMMISSIONER IS AUTHORIZED
TO CHARGE ANY DEFICIENCY IN THE
FEES FOR THIS PAPER TO DEPOSIT
ACCOUNT NO. 23-0975

Sir:

One sheet of formal (A4P) drawings (Figs. 12 and 13) are submitted herewith.

Respectfully submitted,

Yoshio YANASE et al.

By:

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